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Substitute for Form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Application Number	10/802,139
		Filing Date	March 17, 2004.
		First Named Inventor	Kazuhiko OMOTE
		Group Art Unit	2853
		Examiner Name	Not Yet Assigned / K. Suchekla
Sheet	1	Attorney Docket Number	04176/LH

U.S. PATENT DOCUMENTS

Exam. Inits*	Cite No ¹	Document Number	Kind Code ²	Name of Patentee or Applicant	Publication Date MM-DD-YYYY	Relevant Portion

FOREIGN PATENT DOCUMENTS

Exam. Inits*	Cite No ¹	Offc ³	Document Number ⁴	Kind Code ⁵	Name of Patentee or Applicant	Publication Date MM-DD-YYYY	Relevant Portion	T ⁶
W	A	JP	11-304731	A	RIGAKU DENKI KK	11-05-1999		X*
			*English Language Abstract only					

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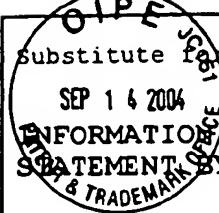
¹ Unique citation designation number. ² See kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Place a check here if English translation is attached.

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DISCLOSURE STATEMENT BY APPLICANT

				Application Number	10/802,139
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				Group Art Unit	2882
				Examiner Name	K. Suchocki
Sheet	1	of	3	Attorney Docket Number	04176/LH

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Examiner Signature

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DATE MAILED: September 14, 2004

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				Examiner Name	<i>K Suchekci</i>
Sheet	2	of	3	Attorney Docket Number	04176/LH

OTHER DOCUMENTS - NON-PATENT LITERATURE DOCUMENTS

Examiner Initials ¹	Cite No. ¹	Include name of author (in CAPITAL LETTERS), title of article, title of item, date, page(s), volume-issue number(s), publisher, city and/or country where published	T ²
<i>NO</i>		X. X. JIANG et al: "STUDY OF STRAIN AND COMPOSITION OF THE SELF-ORGANIZED GE DOTS BY GRAZING INCIDENT X-RAY DIFFRACTION", NUCLEAR INSTRUMENTS & METHODS IN PHYSICS RESEARCH SECTION - A: ACCELERATORS, SPECTROMETERS, DETECTORS AND ASSOCIATED EQUIPMENT, NORTH-HOLLAND PUBLISHING COMPANY, Amsterdam, NL, Vol. 467-468, 21 July 2001 (2001-07-21), pages 362-365, XP004297870, ISSN: 0168-9002. * Chapter "2. Experimental" on pages 363-364. - *reference 12*.	
<i>NO</i>		X. JIANG et al: "STATUS OF THE 4WIC BEAMLINE AND THE DIFFUSE SCATTERING EXPERIMENTAL STATION AT THE BEIJING SYNCHROTRON RADIATION FACILITY", NUCLEAR INSTRUMENTS & METHODS IN PHYSICS RESEARCH SECTION - B: BEAM INTERACTIONS WITH MATERIALS AND ATOMS, NORTH-HOLLAND PUBLISHING COMPANY, Amsterdam, NL, Vol. 129, No. 4, 1 September 1997 (1997-09-01), pages 543-547, XP004089038, ISSN: 0168-583X. *Chapter "3. X-Ray Diffuse Scattering Station" - *Figure 2*.	
<i>NO</i>		M. S. GOORSKY et al: "GRAZING INCIDENCE IN-PLANE DIFFRACTION MEASUREMENT OF IN-PLANE MOSAIC WITH MICROFOCUS X-RAY TUBES", CRYSTAL RESEARCH AND TECHNOLOGY, 2002, WILEY-VCH VERLAG BERLIN GmbH, Germany, "Online!", Vol. 37, No. 7, pages 645-653, XP002289273, ISSN: 0232-1300, Retrieved from the Internet: <URL: http://www.crystalresearch.com/crt/ab37/645_a.pdf >, retrieved on 2004-07-21!, *Chapter "Experimental Requirements"*.	
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<i>NO</i>		LICAI JIANG et al: "APPLICATION OF MULTILAYER OPTICS TO X-RAY DIFFRACTION SYSTEMS", THE RIGAKU JOURNAL, "Online!", Vol. 18, No. 2, 2001, pages 13-22, XP002289275, Retrieved from the Internet: <URL: http://www.rigakumsc.com/journal/Vol18.2.2001/Jiang.pdf >, retrieved on 2004-07-21!, *page 19, last paragraph - page 20, paragraph 1, Figure 13.*	
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<i>NO</i>		A. K. MALHOTRA et al: "IN SITU/EX SITU X-RAY ANALYSIS SYSTEM FOR THIN SPUTTERED FILMS", SURF COAT TECHNOL.: SURFACE & COATINGS TECHNOLOGY, Nov. 10, 1998, Elsevier Science S.A., Lausanne, Switzerland, Vol. 110, No. 1-2, 10 November 1998 (1998-11-10), pages 105-110, XP002288818 - *page 106*.	
<i>NO</i>		"ULTIMA III", RIGAKU, "Online!", 4 February 2004 (2004-02-04), XP002289277, Retrieved from the Internet: <URL: http://www.rigakumsc.com/xrd/ultima.html >, retrieved on 2002-07-21, *the whole document*.	
Examiner Signature		Date Considered	06/09/05

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XO		Y. HIRAI et al: "THE DESIGN AND PERFORMANCE OF BEAMLINE BL16XU AT SPRING-8", NUCLEAR INSTRUMENTS & METHODS IN PHYSICS RESEARCH, SECTION - A: ACCELERATORS, SPECTROMETERS, DETECTORS AND ASSOCIATED EQUIPMENT, NORTH-HOLLAND PUBLISHING COMPANY, Amsterdam, NL, Vol. 251, No. 2-3, 2 April 2004 (2004-04-01), pages 538-548, XP004498331, ISSN: 0168-9002, *Chapter "2.5..2. X-ray diffractometer system", on pages 545, 546* - "reference 22".	

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